Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/766,818	YOSHIDA, MASAHITO	
Examiner	Art Unit	
Shih-wen Hsieh	2861	

SEARCHED			
Class	Subclass	Date	Examiner
347	22,29,33 32,35,36 31	12/23/2005	SWH
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEA	NOTES RCH STRATEGY	′)
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